



Removal of ^{222}Rn daughters from metal surfaces

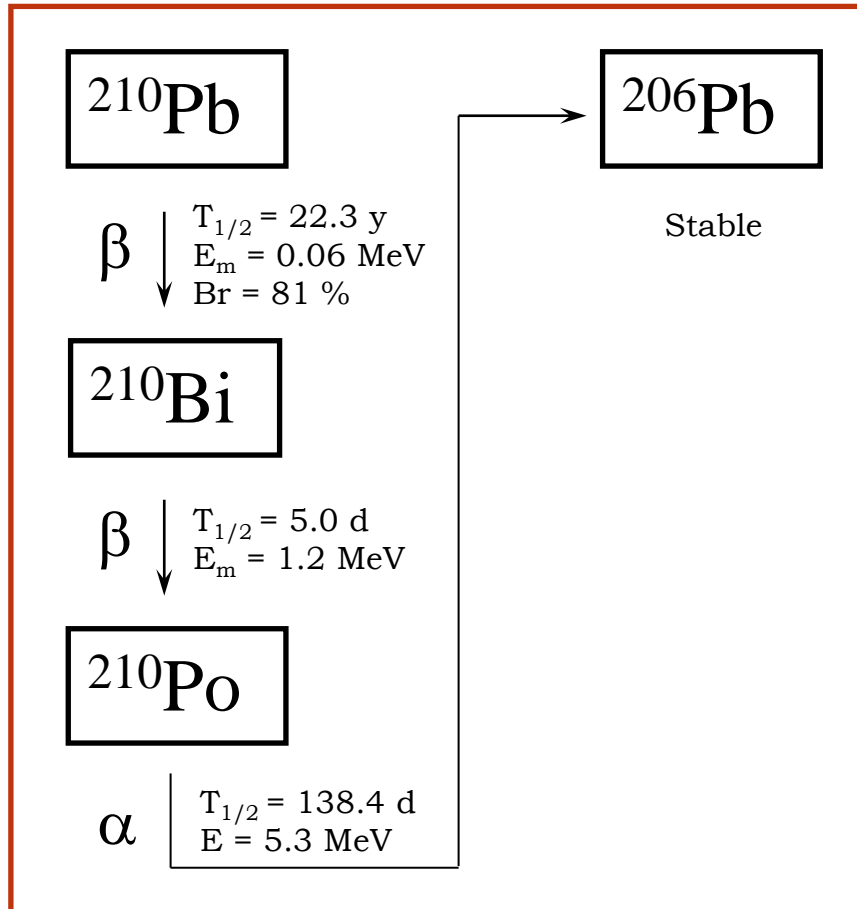
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Outline

- Motivation
- Etching/electropolishing of artificially contaminated samples
- Tests of naturally contaminated samples
- Bulk ^{210}Po assay
- Conclusions

Motivation



- Disequilibrium in the chain
 $A_{\text{Rn}} \neq A_{\text{pb}}$
- In fresh material usually
 $A_{\text{Pb}} \neq A_{\text{Po}}$
- Each isotope should be investigated separately
- Pb may be plated out or implemented into the surface thus Rn-free atmosphere is needed
- ^{210}Bi :
 - pure β -emitter
- ^{210}Po :
 - degraded α s
 - source of ns (α, n) important for DM searches
 - difficult to remove from surfaces

Artificially contaminated samples

- Samples in form of discs with 50 mm diameter
- To increase the sensitivity samples were artificially loaded with ^{210}Pb , ^{210}Bi and ^{210}Po :
 - placed in a strong ^{222}Rn source for several months (^{210}Po specific activities of $\approx 100 \text{ Bq/m}^2$)
- Screening of ^{210}Po with an *alpha* spectrometer:
 - 50 mm Si-detector, bkg $\approx 2 \text{ } \alpha/\text{d}$ (1 – 10 MeV)
 - sensitivity $\approx 20 \text{ mBq/m}^2$ (100 mBq/kg, ^{210}Po)
- Screening of ^{210}Bi with a *beta* spectrometer:
 - 2 \times 50 mm Si(Li)-detectors, bkg $\approx 0.18/0.40 \text{ cpm}$
 - sensitivity $\approx 10 \text{ Bq/kg}$ (^{210}Bi)
- Screening of ^{210}Pb (46.6 keV line) with a *gamma* spectrometer:
 - 16 % HPGe detector with an active and a passive shield

Artificially contaminated samples

Activity reduction factors after etching / electropolishing

Germanium

Isotope	Copper	Stainless steel	NPGe	HPGe
^{210}Pb	50 / 300	100 / 400	100 / –	700 / –
^{210}Bi	50 / 300	100 / 800	400 / –	800 / –
^{210}Po	1 / 400	20 / 700	1000 / –	100 / –

- Copper
 - etching: 5 min in (1% H_2SO_4 + 3% H_2O_2) and 5 min in 1% citric acid
 - electro-polishing (electrolyte): 85 % H_3PO_4 + 5 % 1-butanol ($\text{C}_4\text{H}_{10}\text{O}$)
- Stainless steel
 - etching: (20 % HNO_3 + 1.7 % HF) and 15 % HNO_3
 - electro-polishing (electrolyte): 40 % H_3PO_4 + 40 % H_2SO_4 + 3 % CrO_3
- Germanium
 - etching: CP4 solution (45.45 ml HNO_3 + 27.27 ml HF + 27.27 ml CH_3COOH + 0.5 ml Br for 100 ml solvent) done by Canberra-France in Lingolsheim in cooperation with MPP Munich

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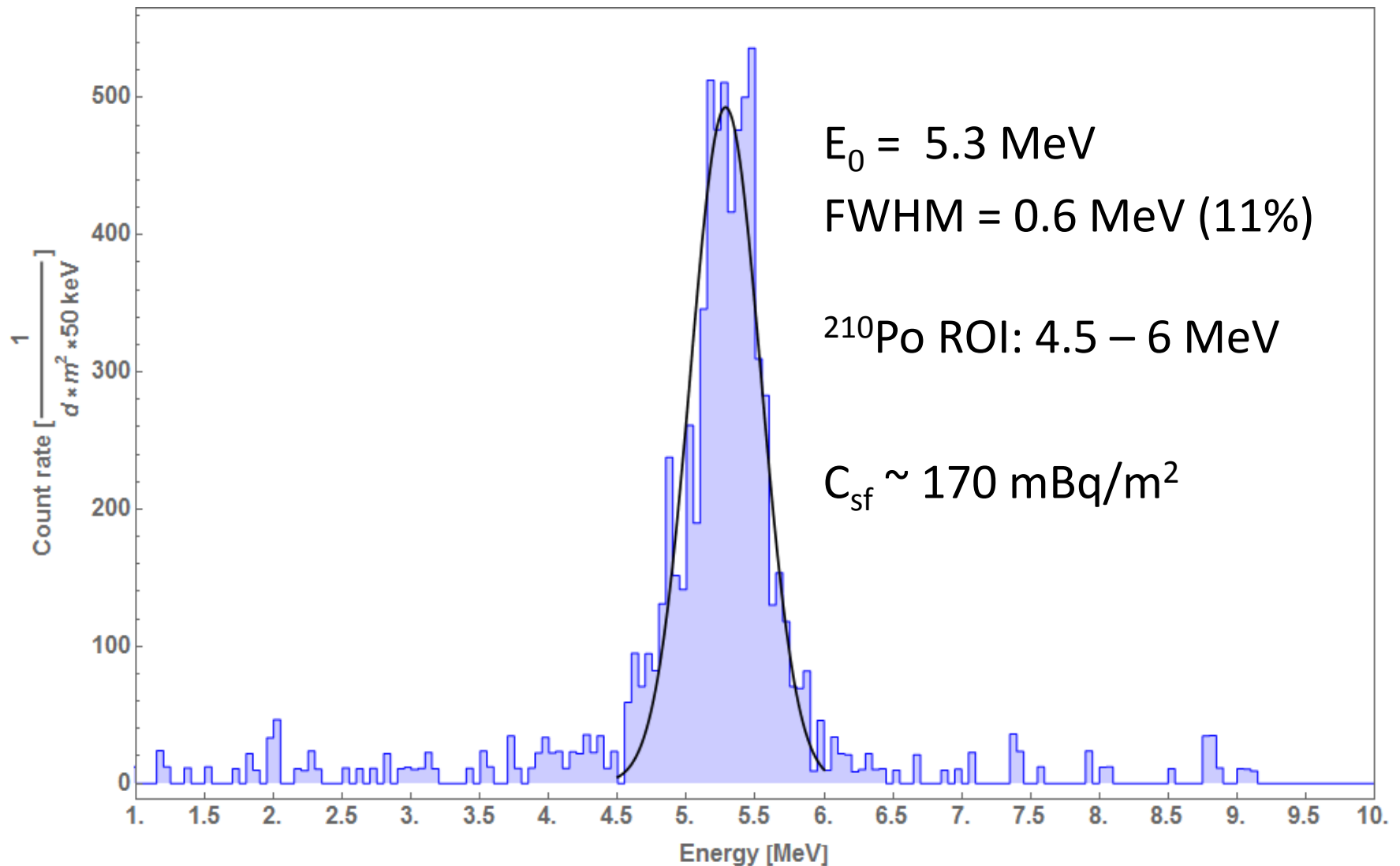
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XIA Large Surface Detector

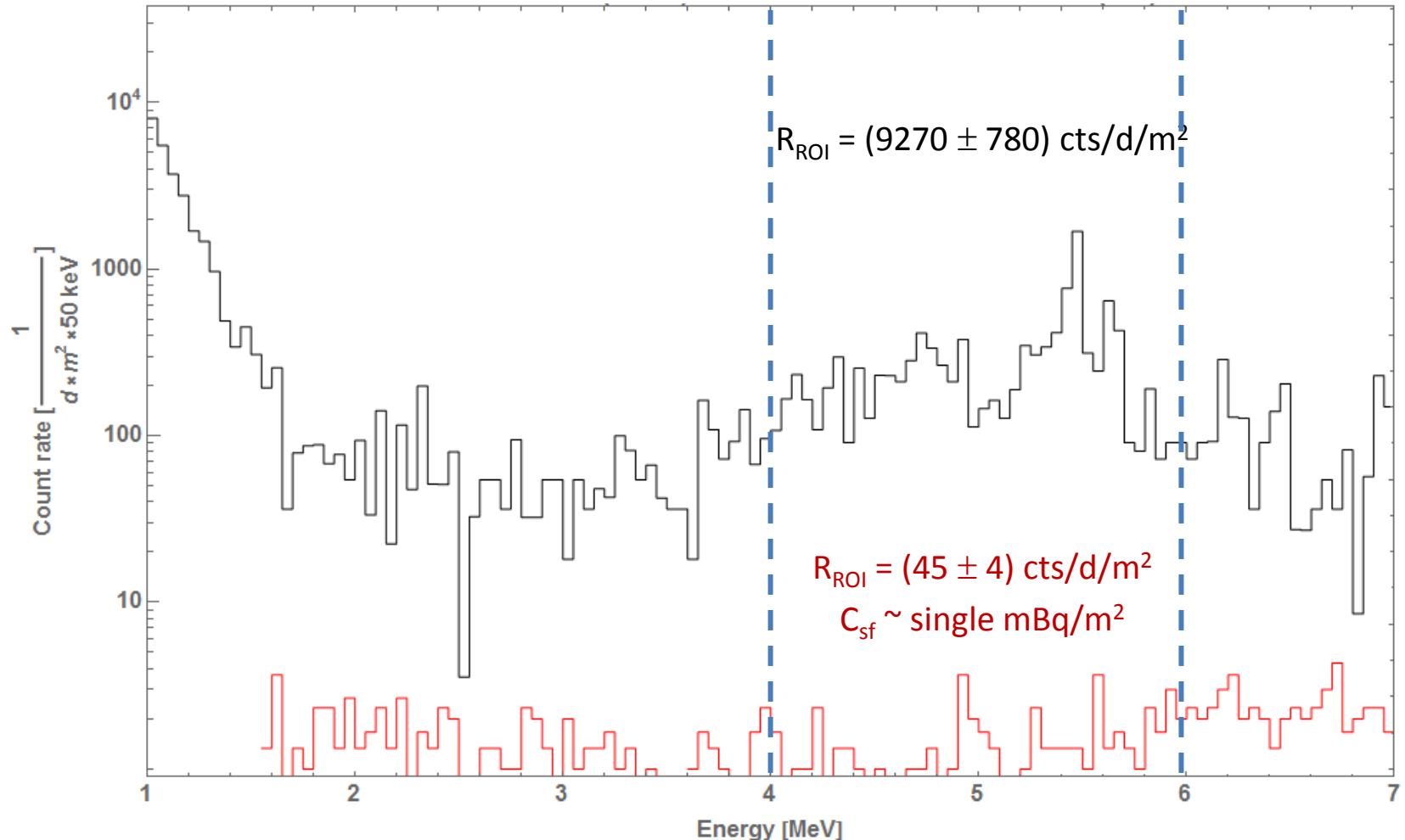


- Only ^{210}Po studied
- Low background, large surface (LBS) alpha spectrometer
- Ar as counting gas (3.5 L/min)
- Sample size: 43×43 cm or 30 cm diameter disc, 1 mm thick
- PSD + veto guard (**alphas**, **mid-air**s, **ceiling**, **rounds**)

Copper sheet with surface ^{210}Po (air-born)



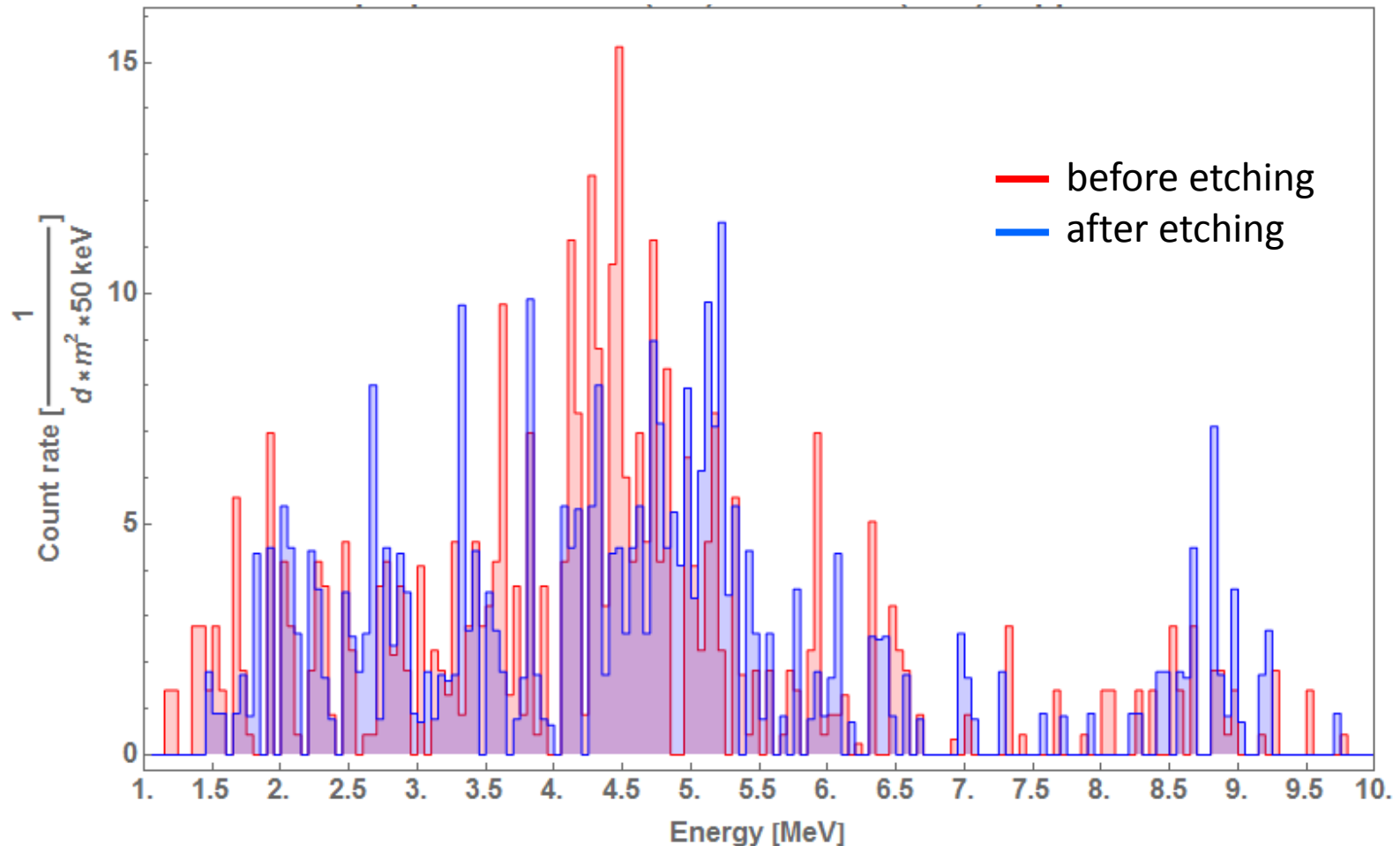
XIA Large Surface Detector – background



- Low background ORTEC α detector (40 mm diameter) at LNGS (*Appl. Rad. Isot.* 81 (2013) 146) vs. **XIA Ultra-Low 1800 on the surface: factor 200 improvement**

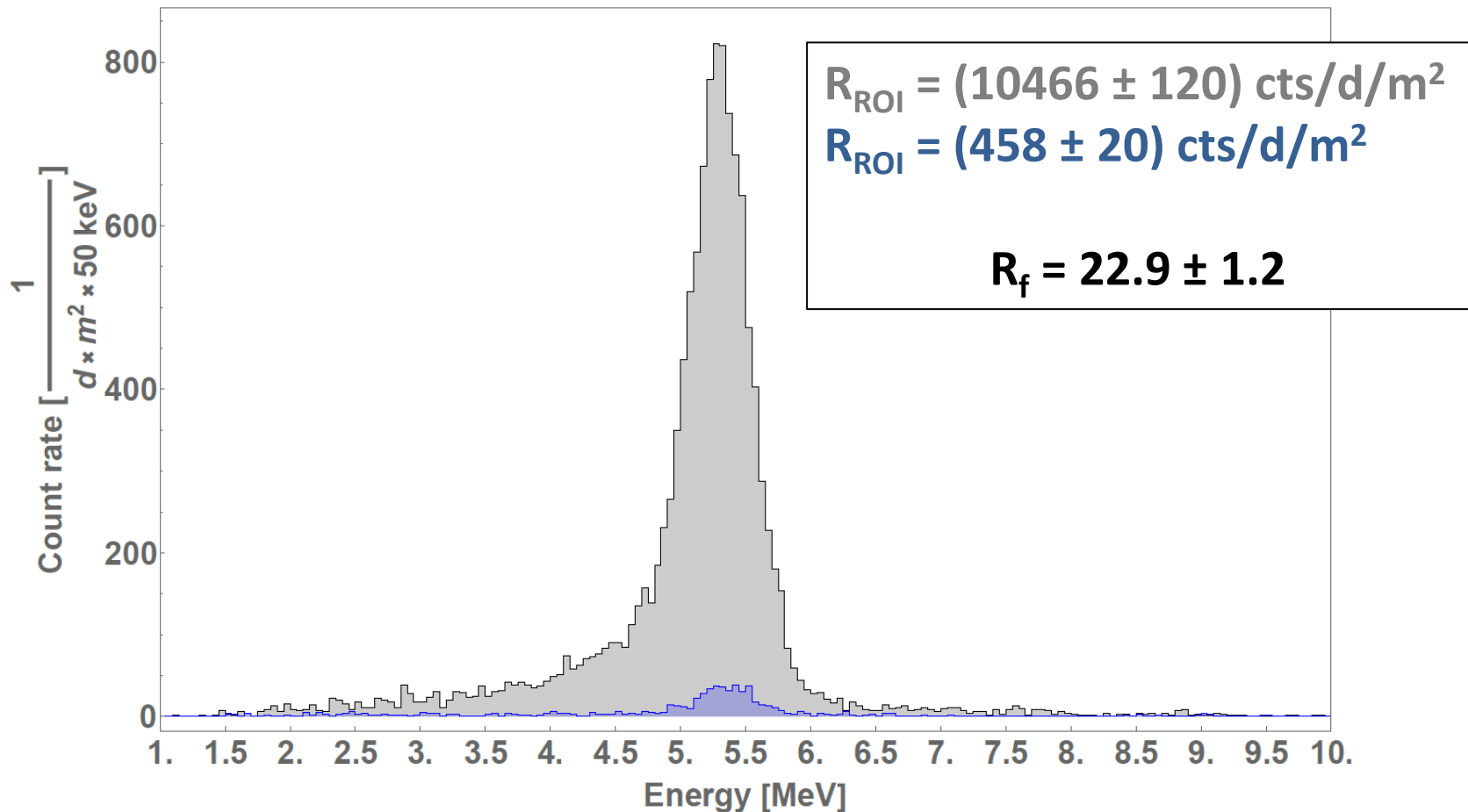
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Etching of clean Cu (ETP)



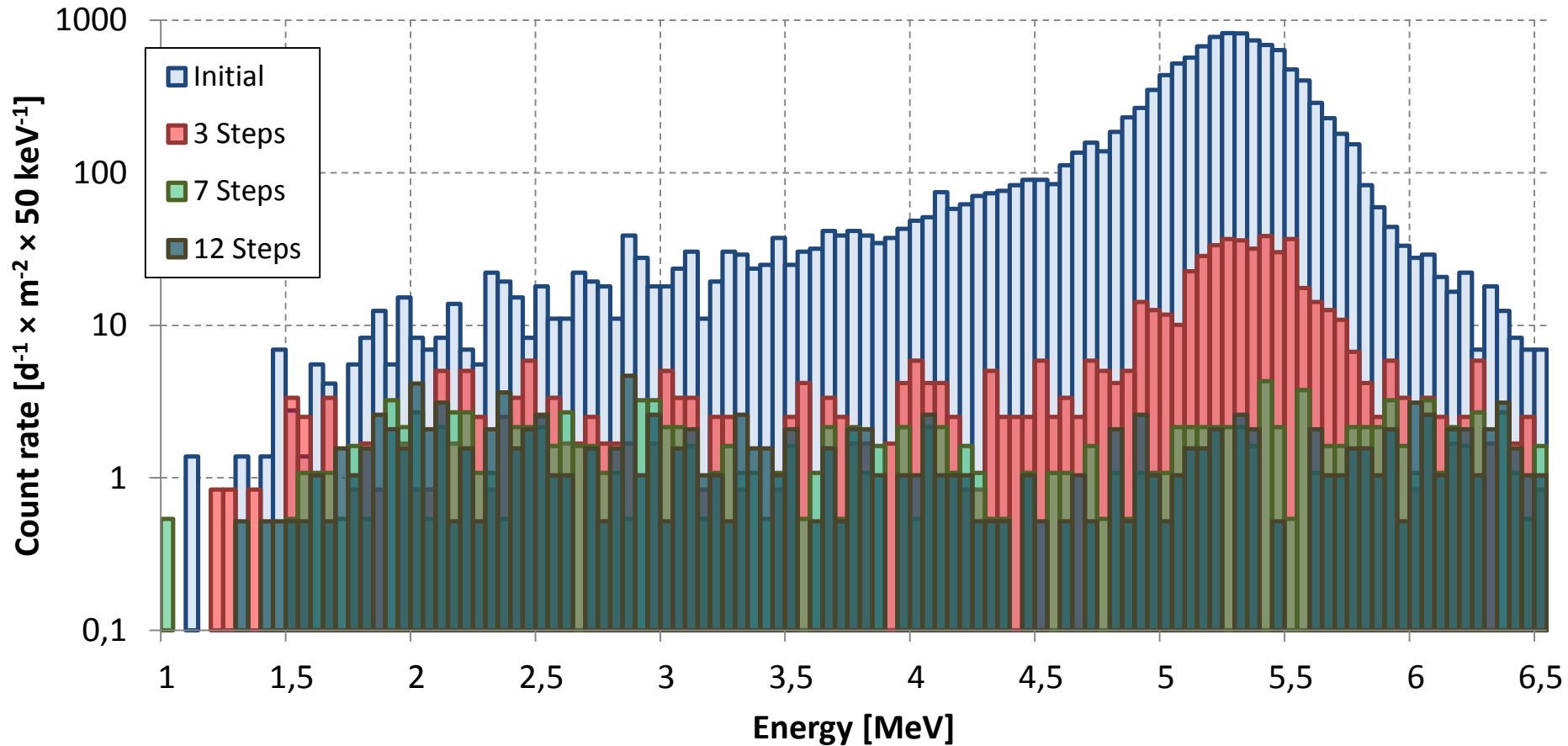
- Etching procedure: 5 min in a mixture of: 1% H_2SO_4 + 3% H_2O_2
- Washing in high-purity deionized water ($18 \text{ M}\Omega \times \text{cm}$)
- No effect observed for surface ^{210}Po (at the level of $\sim 1 \text{ mBq}/\text{m}^2$)

Dynamic etching

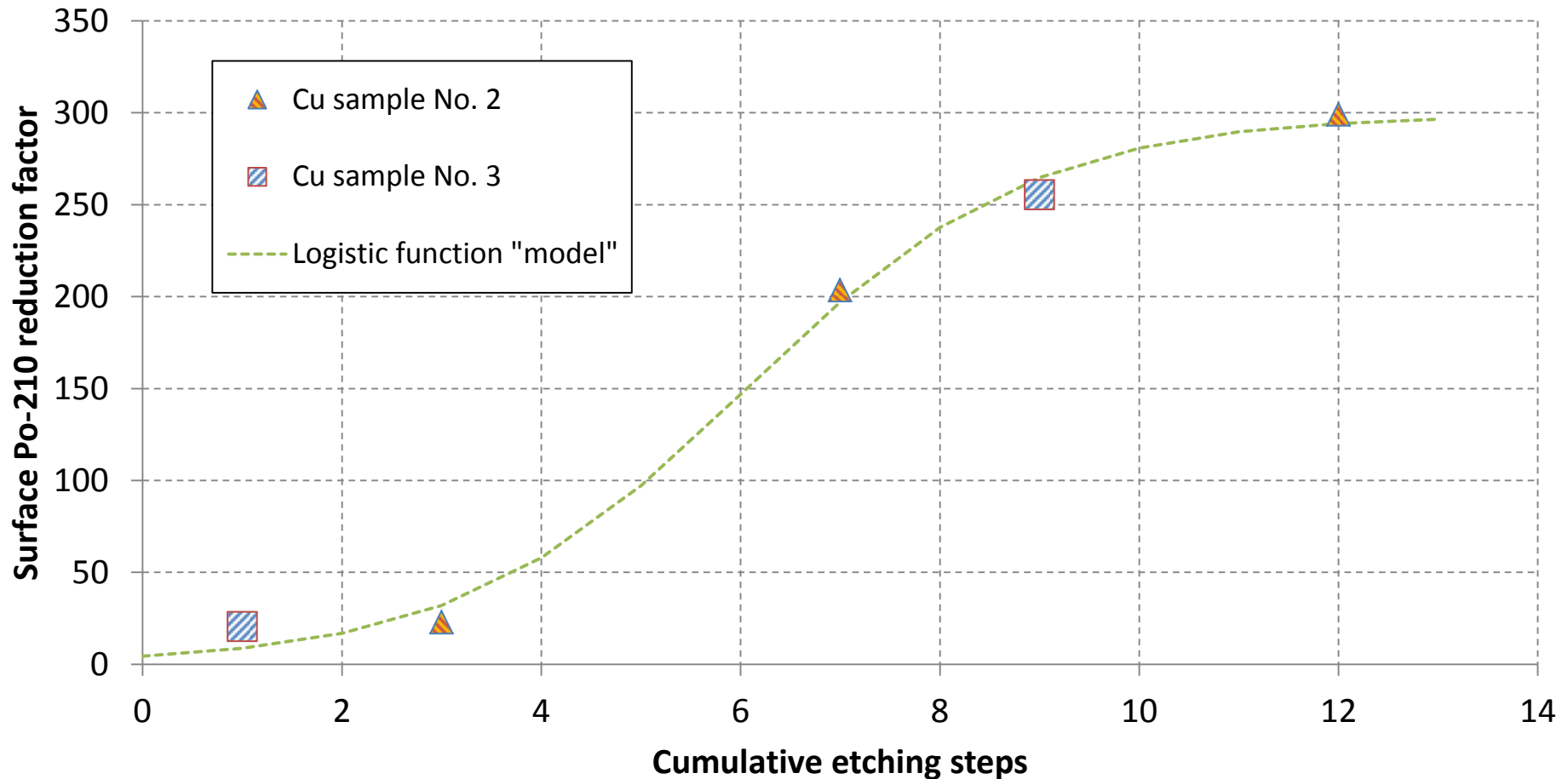


- Etching procedure: 4×1 min in a mixture of 1% H_2SO_4 + 3% H_2O_2
- Passivation with 1% citric acid at the end
- Washing in high-purity deionized water ($18 \text{ M}\Omega \times \text{cm}$)

Dynamic etching – 3, 7, 12 cumulative steps

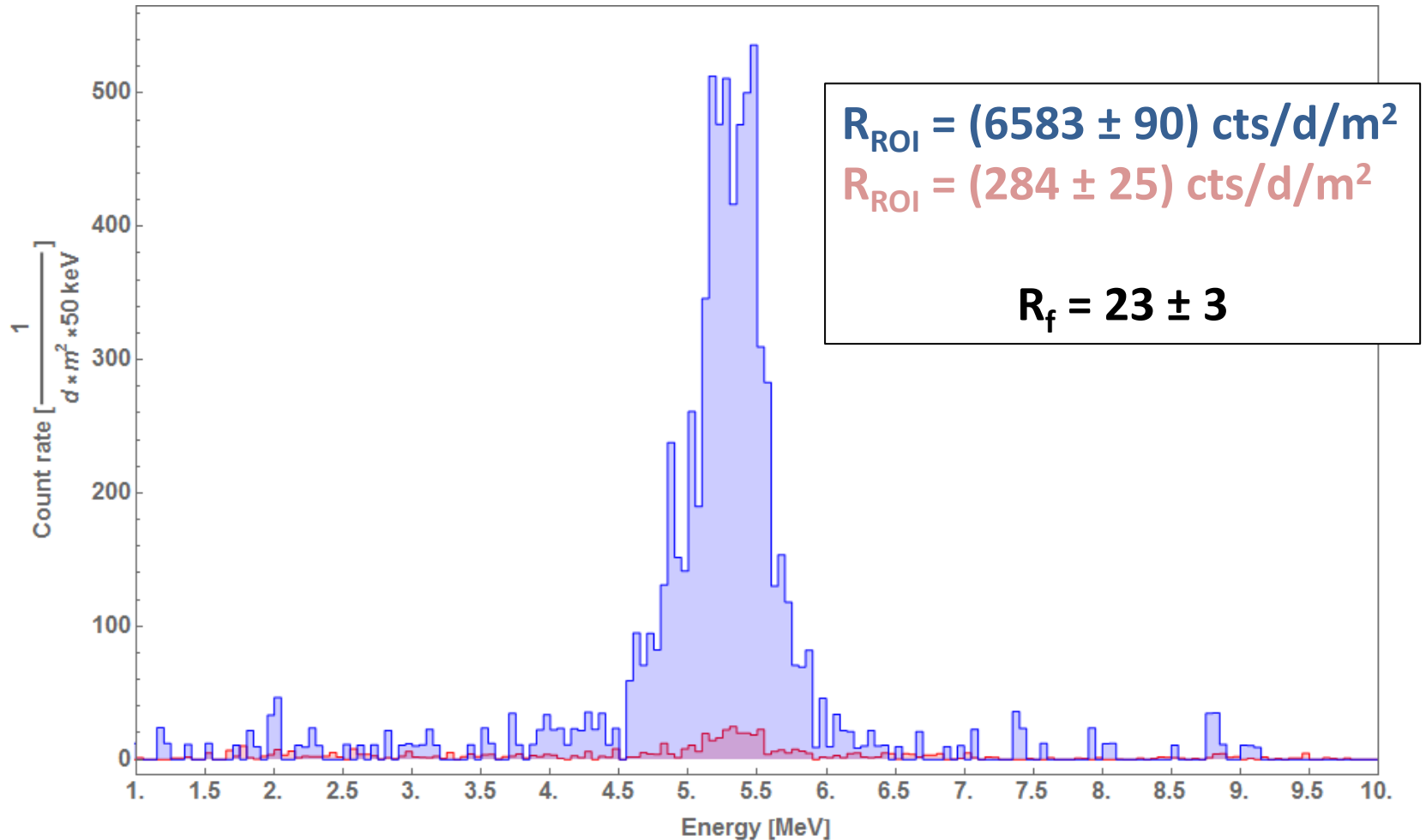


Dynamic etching



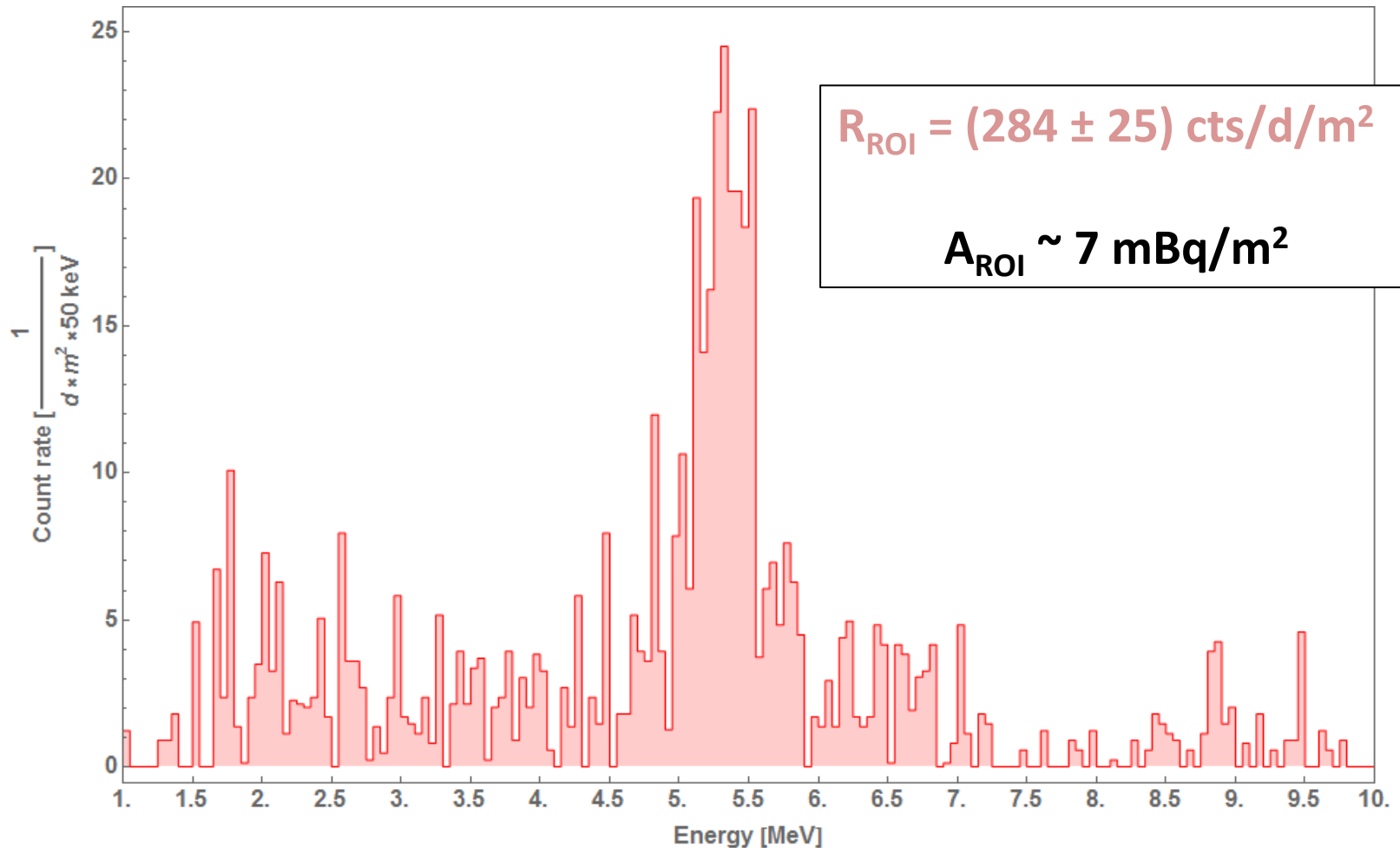
- Energetic washing n-times always with fresh reagents

Electropolishing of copper



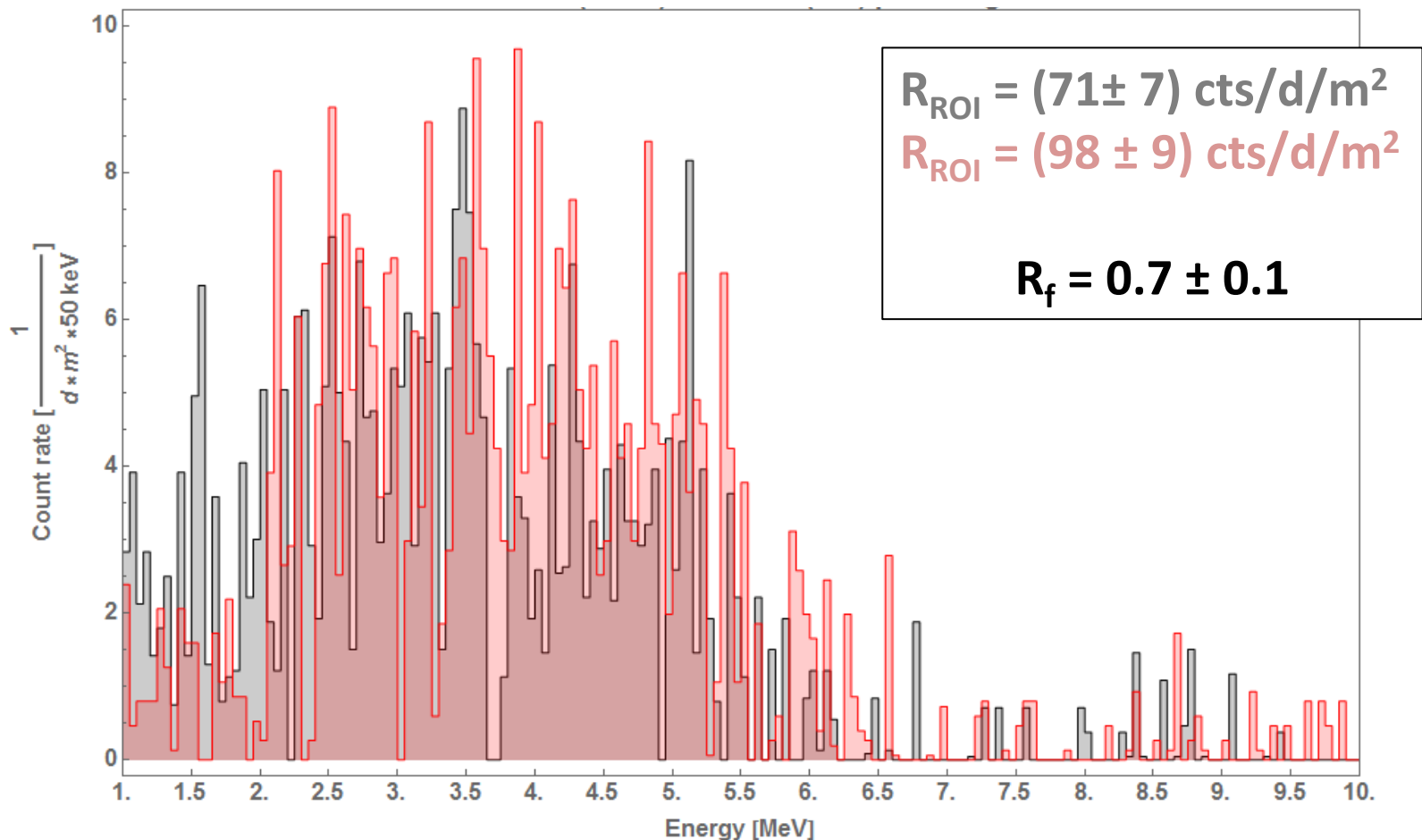
- Polishing solution: 95% H_3PO_4 + 1% 1-butanol
- Polishing conditions: 2.5 A/dm^2 , 3 V, 20 min, 2 cm plate distance, room temperature

Electropolishing of copper



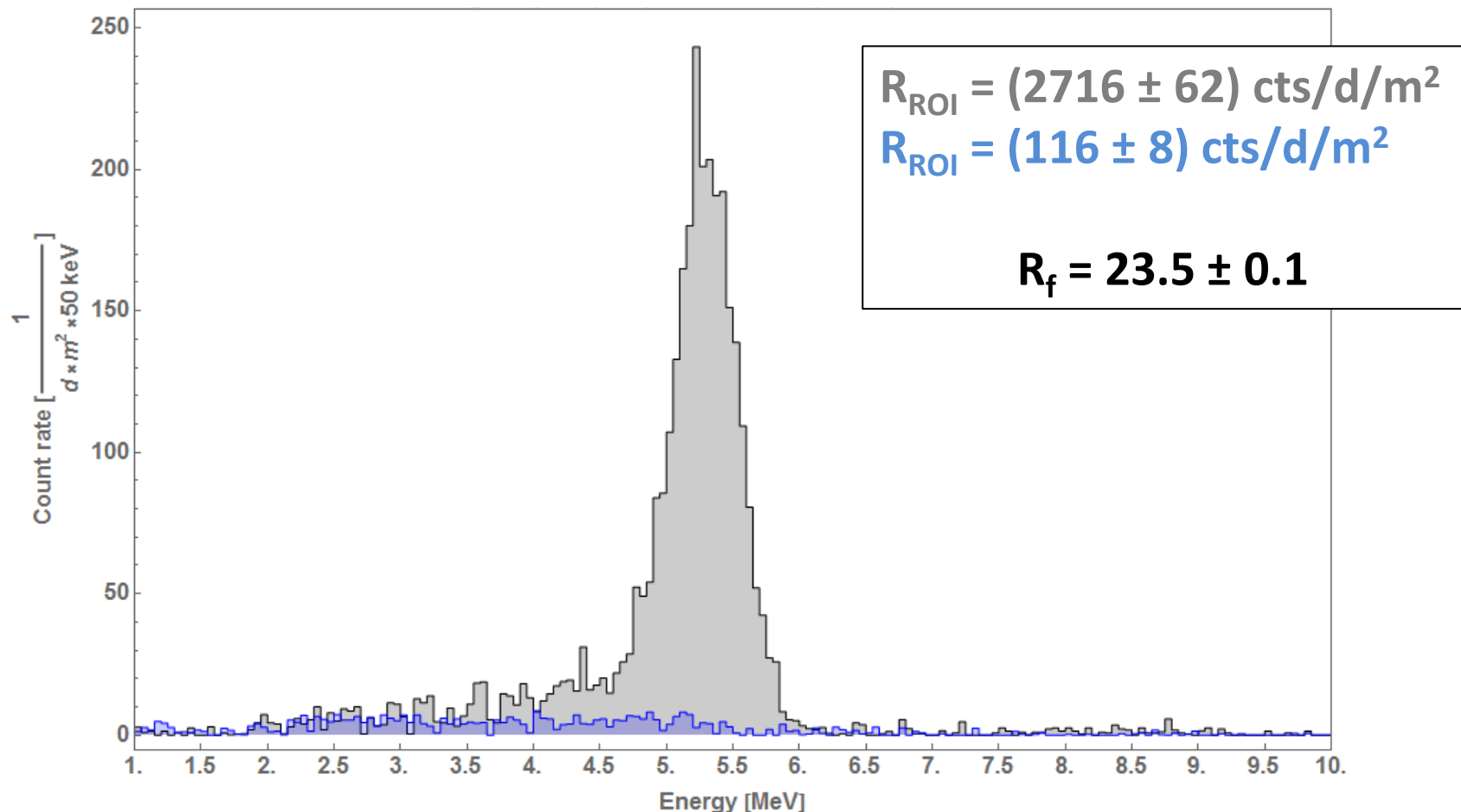
- Polishing solution: 95% H_3PO_4 + 1% 1-butanol
- Polishing conditions: 2.5 A/dm^2 , 3 V, 20 min, 2 cm plate distance, room temperature

Electropolishing of clean stainless steel (SS 1.4301 (304), sheet No. 1)



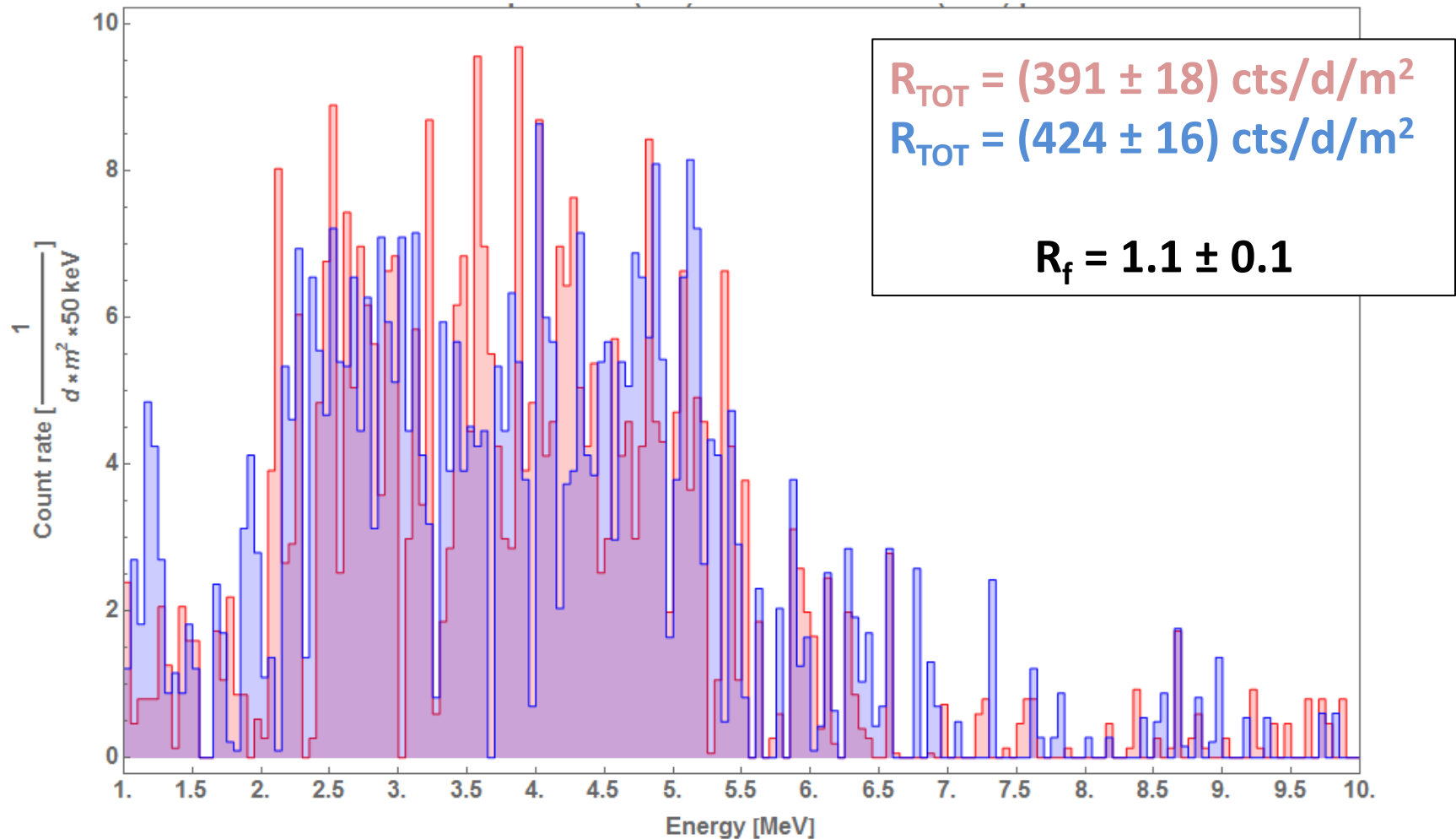
- Polishing mixture: 1:1 of 95% H_2SO_4 and 85% H_3PO_4
- Washing: 5 min in 15% HNO_3 and later in HP water
- Polishing conditions: 2.5 A/dm^2 , 2 V, 25 min, 2 cm plate distance, $T \approx 50 \text{ }^\circ\text{C}$

Electropolishing of stainless steel (SS 1.4301 (304), sheet No. 2)



- Polishing mixture: 1:1 of 95% H_2SO_4 and 85% H_3PO_4
- Washing: 5 min in 15% HNO_3 and later in HP water
- Polishing conditions: 2.5 A/dm^2 , 2 V, 25 min, 2 cm plate distance, $T \approx 50 \text{ }^\circ\text{C}$

Electropolishing of stainless steel (sheet No. 1 and 2 after electropolishing)



- No effect observed for surface ^{210}Po (at the level of $\sim 1 \text{ mBq/m}^2$)

Bulk ^{210}Po assay

First results for bulk ^{210}Po in various metals reported during the ICRM–LLRMT conference in Seattle (Sept. 2016)



Contents lists available at [ScienceDirect](#)

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Studies of surface and bulk ^{210}Po in metals using an ultra-low background large surface alpha spectrometer

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ABSTRACT

First measurements of natural surface and bulk ^{210}Po specific activities for metals are reported. If covered with protective foils, the surfaces did not show indications of ^{210}Po and the obtained upper limits are in the range of single mBq m^{-2} . Weak bulk activities, in the range of $50 - 280 \text{ mBq kg}^{-1}$, were registered for Stainless Steel and Copper, while significant amounts of ^{210}Po , $\sim 1.5 \text{ Bq kg}^{-1}$, were detected in Titanium. One special Teflon sample was investigated with respect to its bulk ^{210}Po .

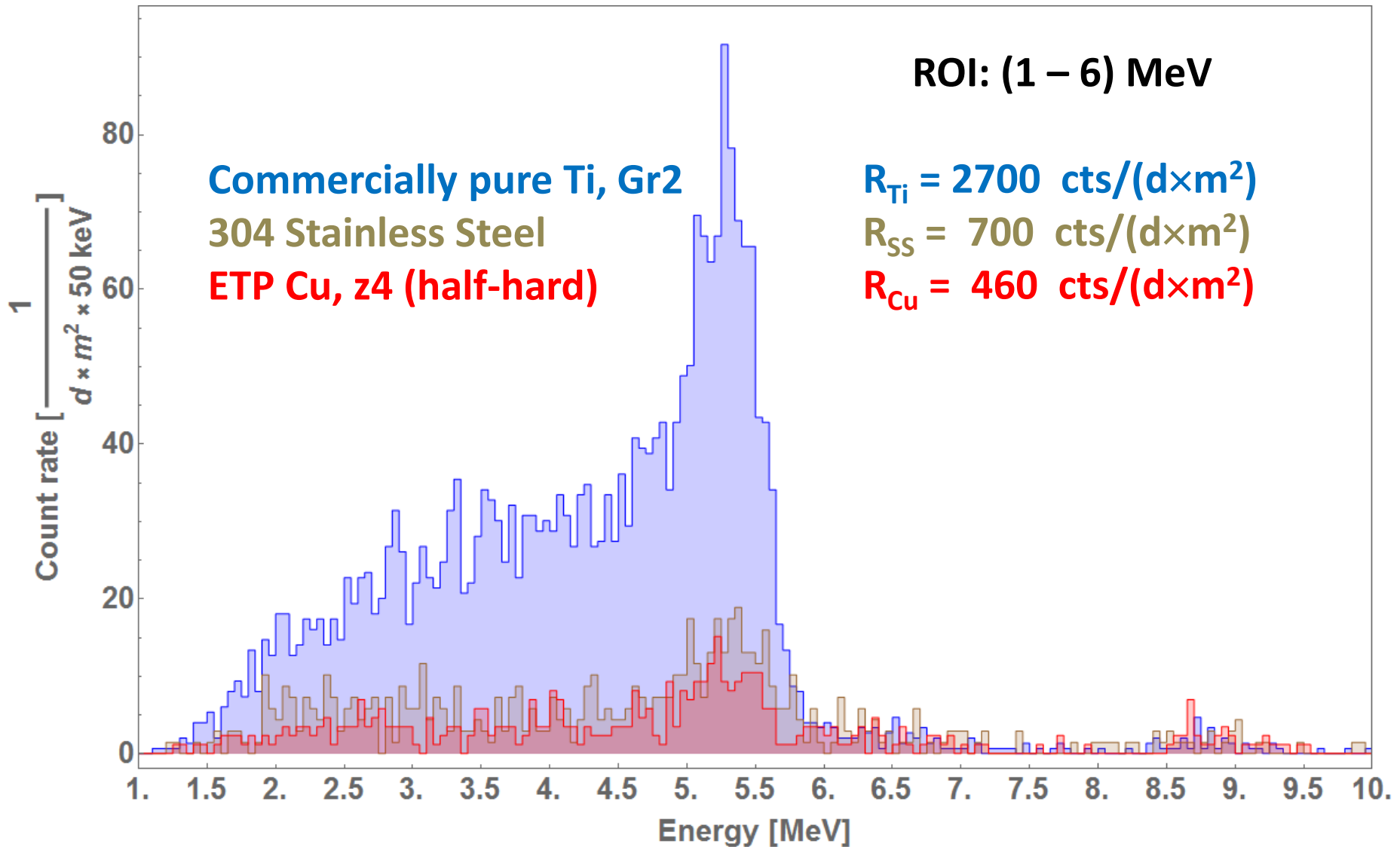
<https://doi.org/10.1016/j.apradiso.2017.01.030>

Bulk ^{210}Po assay

Material	Bulk ^{210}Po [mBq/kg]	Surface ^{210}Po [mBq/m ²]	Remarks
OF Copper	54	≤ 3	z4 (half hard)
ETP Copper	75	≤ 3	z4 (half hard)
„Old” ETP Copper	280	170	z4 (half hard)
Stainless Steel	80	≤ 3	Type 304
Titanium	1500	68	GR2
Teflon	≤ 46	–	High purity, ATP

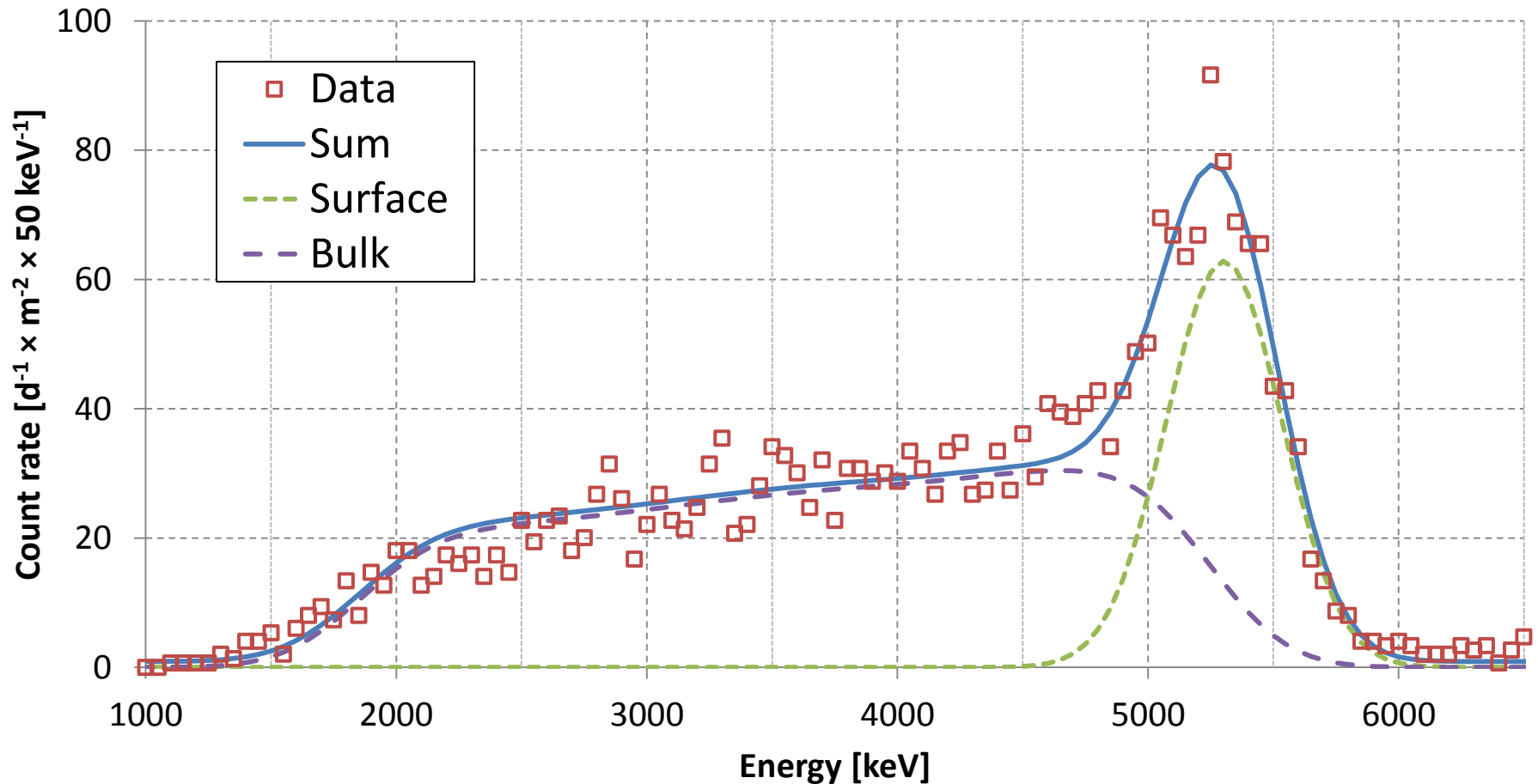
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Bulk ^{210}Po assay



<https://doi.org/10.1016/j.apradiso.2017.01.030>

^{210}Po in/on Titanium after surface treatment (etching)



- The detection efficiencies precisely fixed (spectrum deconvolution)
- $C_{\text{BULK}} = (1.0 \pm 0.1) \text{ Bq/kg}$
- $C_{\text{sf}} = (18.7 \pm 1.0) \text{ mBq/m}^2$

Conclusions

- Copper/stainless steel surfaces protected against air (^{222}Rn) did not show indications of ^{210}Po .
- Etching/electropolishing removes ^{210}Pb , ^{210}Bi and ^{210}Po from metal surfaces, the effect seems to be material- and surface finish dependent. „*Static*” etching did not affect ^{210}Po on copper.
- At the level of mBq/m^2 proper etching/electropolishing does not contaminate surfaces with ^{210}Po .
- For the first time an effect of ^{210}Po activity reduction on copper surface after („*dynamic*”) etching has been observed. High activity reduction factor obtained (~ 300).
- Applied electropolishing procedures reduce the natural ^{210}Po surface activity on copper/steel by a factor up to 25. There is still room for improvements.
- High-sensitivity alpha spectrometers allow for ^{210}Po surface and bulk activity measurements.